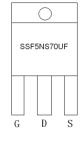
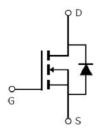


Main Product Characteristics:

V _{DSS}	700V
R _{DS} (on)	1.0Ω (typ.)
I _D	5A ⊕







TO-220F

Marking and pin
Assignment

Schematic diagram

Features and Benefits:

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance



Description:

The SSF5NS70UF series MOSFETs is a new technology, which combines an innovative technology and advance process. This new technology achieves low Rdson, energy saving, high reliability and uniformity, superior power density and space saving.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V	5 ①	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	3.1①	Α
I _{DM}	Pulsed Drain Current ②	15	
P _D @TC = 25°C	Power Dissipation ③	29	W
PD @ 10 = 25 C	Linear Derating Factor	0.23	W/°C
V _{DS}	Drain-Source Voltage	700	V
V _{GS}	Gate-to-Source Voltage	± 30	V
Eas	Single Pulse Avalanche Energy @ L=144.4mH	173	mJ
I _{AS}	Avalanche Current @ L=144.4mH	1.55	Α
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
R _{θJC}	Junction-to-case ③	_	4.3	°CM
$R_{\theta JA}$	Junction-to-ambient (t \leq 10s) (4)	_	62	°CM

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	700	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
		_	1.0	1.25	Ω	V _{GS} =10V,I _D = 1A
D	Static Drain-to-Source on-resistance	_	2.3	_		T _J = 125°C
$R_{DS(on)}$	Static Diani-to-Source on-resistance	_	1.14	1.4	Ω	V _{GS} =10V,I _D = 2.8A
		_	3.0	_	122	T _J = 125°C
V	Gate threshold voltage	2	_	4	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
$V_{GS(th)}$	Gate threshold voltage		2.3	_	V	T _J = 125°C
1	Drain to Source leakage ourrent	_	_	1		$V_{DS} = 700 V, V_{GS} = 0 V$
I _{DSS}	Drain-to-Source leakage current		_	50	μΑ	T _J = 125°C
1	Gate-to-Source forward leakage	_	_	100	nA	V _{GS} =30V
I_{GSS}	Gate-to-Source forward leakage	_	_	-100		V _{GS} = -30V
Q_g	Total gate charge	_	9.8	_	nC	$I_D = 5A$,
Q_gs	Gate-to-Source charge	_	2.7	_		V _{DS} =200V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	3.6	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	9.2	_		
t _r	Rise time	_	5.6	_	ns	V_{GS} =10V, V_{DS} =400V,
t _{d(off)}	Turn-Off delay time	_	23	_		R_{GEN} =10.2 Ω , I_D =1.5A
tf	Fall time	_	13	_		
C _{iss}	Input capacitance	_	343	_		V _{GS} = 0V
Coss	Output capacitance	_	18	_	pF	V _{DS} = 100V
C _{rss}	Reverse transfer capacitance	_	2.9	_		f = 1MHz

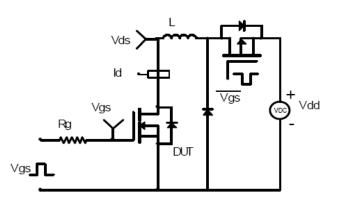
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
-	Continuous Source Current			F (2)	^	MOSFET symbol
I _S	(Body Diode)	_	_	5 ①	Α	showing the
I _{SM}	Pulsed Source Current			15	А	integral reverse
	(Body Diode)	_	_			p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.83	1.2	V	I _S =2.8A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	99	_	nS	$T_J = 25$ °C, $I_F = 1.5$ A,
Q _{rr}	Reverse Recovery Charge	_	466	_	nC	di/dt = 100A/μs

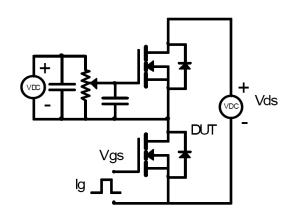


Test circuits and Waveforms

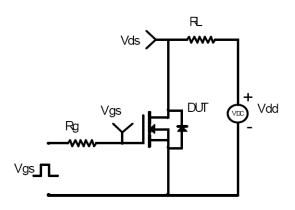
EAS Test Circuit:



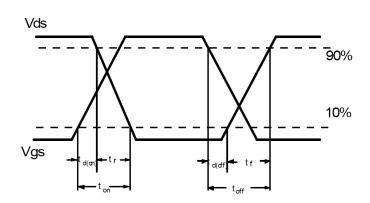
Gate charge test circuit:



Switching Time Test Circuit:



Switching Waveforms:

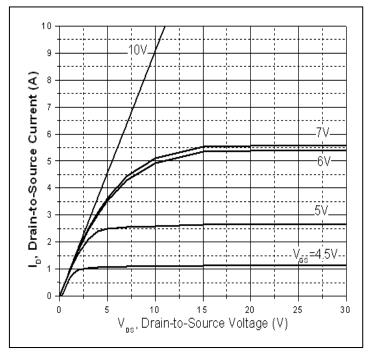


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\texttt{6JA}}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics



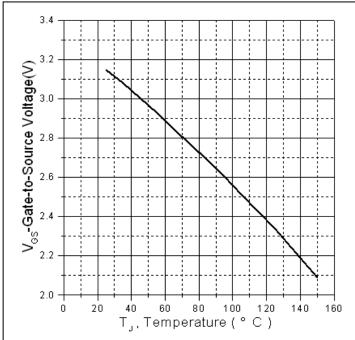


Figure 1: Typical Output Characteristics

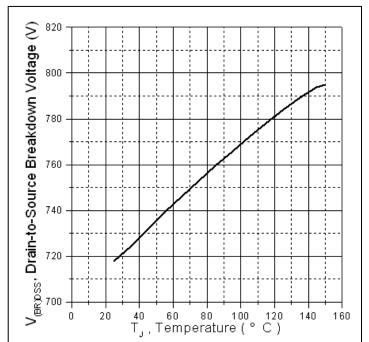


Figure 3. Drain-to-Source Breakdown Voltage Vs.

Case Temperature

Figure 2. Gate to source cut-off voltage

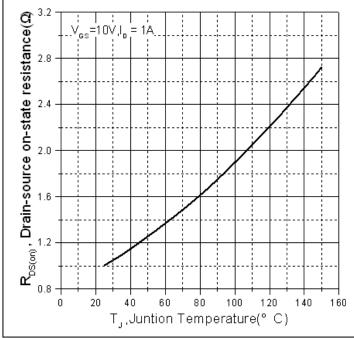


Figure 4: Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics

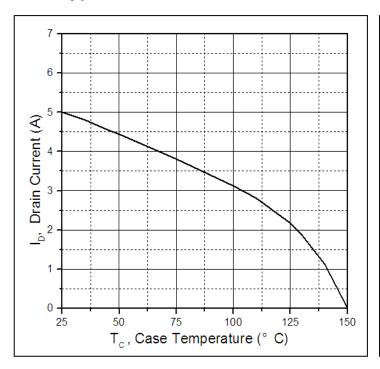


Figure 5. Maximum Drain Current Vs. Case Temperature

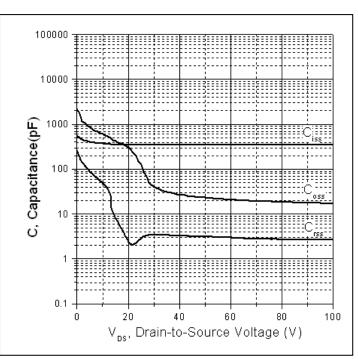


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

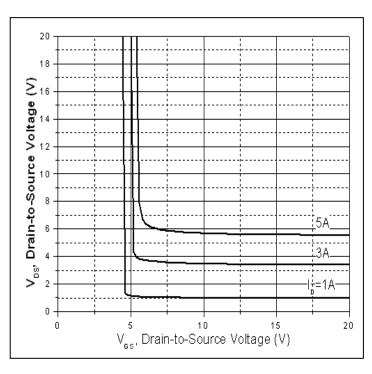


Figure7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage

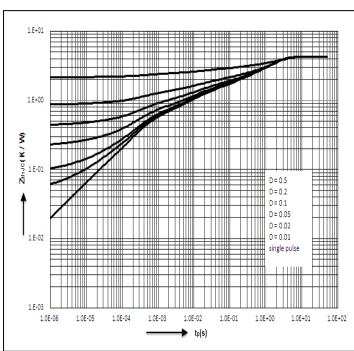
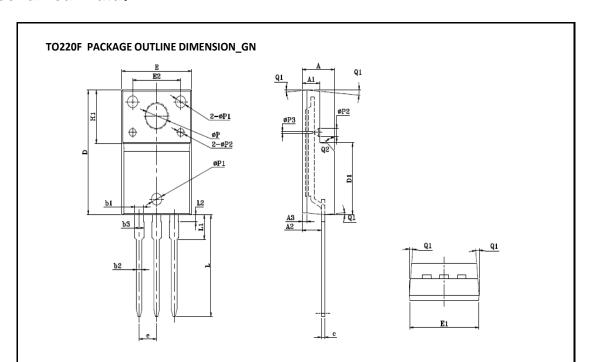


Figure8. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



Cumb al	Dime	Dimension In Millimeters			Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max		
Е	9.960	10.160	10.360	0.392	0.400	0.408		
E1	9.840	10.040	10.240	0.387	0.395	0.403		
E2	6.800	7.000	7.200	0.268	0.276	0.283		
Α	4.600	4.700	4.800	0.181	0.185	0.189		
A1	2.440	2.540	2.640	0.096	0.100	0.104		
A2	2.660	2.760	2.860	0.105	0.109	0.113		
A3	0.600	0.700	0.800	0.024	0.028	0.031		
С	-	0.500	-	-	0.020	-		
D	15.780	15.870	15.980	0.621	0.625	0.629		
D1	8.970	9.170	9.370	0.353	0.361	0.369		
H1	6.500	6.700	6.800	0.256	0.264	0.268		
е		2.54BSC	•	0.10BSC				
ΦР	3.080	3.180	3.280	0.121	0.125	0.129		
ФР1	1.400	1.500	1.600	0.055	0.059	0.063		
ФР2	0.900	1.000	1.100	0.035	0.039	0.043		
ФР3	0.100	0.200	0.300	0.004	0.008	0.012		
L	12.780	12.980	13.180	0.503	0.511	0.519		
L1	2.970	3.170	3.370	0.117	0.125	0.133		
L2	0.830	0.930	1.030	0.033	0.037	0.041		
Q1	3°	5°	7°	3°	5°	7°		
Q2	43°	45°	47°	43°	45°	47°		
b1	1.180	1.280	1.380	0.046	0.050	0.054		
b2	0.760	0.800	0.840	0.030	0.031	0.033		
b3	-	-	1.420	-	-	0.056		





Ordering and Marking Information

Device Marking: SSF5NS70UF

Package (Available)
TO-220F
Operating Temperature Range
C: -55 to 150 °C

Devices per Unit

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Type	Tube	Box	Box	Boxes/Carton	Box
					l l
				Box	

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			





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Customer Service

Worldwide Sales and Service:

Sales@silikron.com

Technical Support:

Technical@silikron.com

Suzhou Silikron Semiconductor Corp.

11A, 428 Xinglong Street, Suzhou Industrial Park, P.R.China

TEL: (86-512) 62560688 **FAX:** (86-512) 65160705 **E-mail:** Sales@silikron.com